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(54) **METHOD AND DEVICE FOR DETERMINING TEST SETS OF OPERATING PARAMETER VALUES FOR AN ELECTRONIC COMPONENT**

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This patent is subject to a terminal disclaimer.

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CPC ***G01R 31/2601*** (2013.01); ***G01R 31/2879*** (2013.01); ***G01R 31/2894*** (2013.01); ***H01L 22/14*** (2013.01); ***H01L 22/20*** (2013.01)

(58) **Field of Classification Search**

CPC G01R 31/2879

USPC 702/123

See application file for complete search history.

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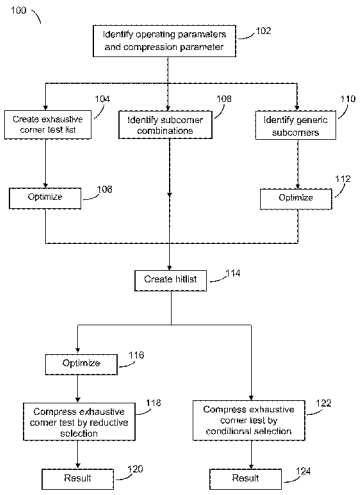
(57) **ABSTRACT**

A method for determining test sets of operating parameter values for an electronic component, the method including: determining a first set of intermediate sets, each intermediate set containing a combination of a first number of operating parameters of the electronic component; determining a second set of reference sets, wherein the second set contains a union of sets, each set comprising all possible combinations of parameter values for the parameters of a respective intermediate set; selecting a third set with a second number of test sets out of a set of predefined sets, wherein each predefined set comprises a different combination of the parameter values for all parameters from the predefined parameter set, such that the second set is a subset of a union of a number of sets, each set comprising all possible combinations of the first number of parameter values for all parameters of a respective test set.

10 Claims, 3 Drawing Sheets